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|-----------------------------------|--|---------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination UEYANAGI ET AL. | |
| | | Examiner Wai Lun Leung | Art Unit 2613 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-6,775,480 B1 | 08-2004 | Goodwill, Dominic John | 398/158 |
| * | B | US-6,381,055 B1 | 04-2002 | Javitt et al. | 398/131 |
| * | C | US-5,663,944 A | 09-1997 | Mun, Jong-kuk | 369/121 |
| * | D | US-6,721,510 B2 | 04-2004 | Graves et al. | 398/129 |
| * | E | US-7,120,363 B2 | 10-2006 | Andreu-von Euw et al. | 398/129 |
| * | F | US-2003/0213787 A1 | 11-2003 | Dunsky et al. | 219/121.75 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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